

# Search Notes



Application No.

10/607,741

Examiner

Hieu Phan

Applicant(s)

CLERC ET AL.

Art Unit

3738

## SEARCHED

Class	Subclass	Date	Examiner
623	1.13-1.2	3/22/2004	JP
623	1.27	3/22/2004	JP
623	1.35	3/22/2004	TO

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR